

Substitute for form 1449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	10/642,305
				Filing Date	August 18, 2003
				First Named Inventor	Hongyong ZHANG et al.
				Art Unit	2811
				Examiner Name	D. Owens
				Attorney Docket Number	740756-2646
Sheet	1	of	7		

U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No.	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicants of Cited Document	Pages, Columns, Figures, etc.	Date, Where Relevant to Appears
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Sheet	3	of	7			
FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Chn No.†	Foreign Patent Document Country Code ³ Number ² Kind Code ⁴ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Paragraphs or Relevant Figures Appear	†*
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				Examiner Name	D. Owens
Sheet	4	of	7	Attorney Docket Number	740756-2646

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS		
Examiner Initials*	Cite No.†	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
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Examiner Signature		Date Considered

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Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark		Attorney Docket: 740756-2646		Sheet 6 of 7 Serial No. 10/642,305	
INFORMATION DISCLOSURE STATEMENT							
(Use several sheets if necessary)							
				Applicant: Hongyong ZHANG et al.			
				Filing Date: August 18, 2003		Group: 2811	
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Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
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Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Attorney Docket: 740756- 2646		Serial No. 10/642,305	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)							
				Applicant: Hongyong ZHANG et al.			
				Filing Date: August 18, 2003		Group: 2811	
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
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	58-002073	01/07/83	Japan			Full	
	58-182816	10/25/83	Japan			Abstract	
	59-040580	03/06/84	Japan			Abstract	
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